Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/707,356	LEE ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

	SEARCHED		
Class	Subclass	Date	Examiner
29	592.1 832	5/26/2006	PK
250	208.1 553		
257	40		
315	169.3		
	169.4 504		
345	205 207	\bigvee	
		_	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Consulted by Thuy Tran (315) No Search	2/14/2006	РК
Eddie Lee (257) No Search	3/21/2006	РК
Marie Yamnitzky (428) No Search	2/13/2006	PK
Review the US Applicantion 10/707,355 (Pending)	5/26/2006	PK
Text Search EAST/NPL (IEEE)	5/26/2006	PK